

No.	1893	PCN Date	September 30, 2011	Effective Date	December 30, 2011
Title	Alternative Format for Trace Codes				

Approval Notice

Everspin Inc. will consider this change accepted unless specific conditions for acceptance are provided in writing within 30 days of receipt of this notice.

Description and Purpose – Affected Products

To improve manufacturing efficiency and package marking readability Everspin may employ a simplified trace code as an alternative product marking format.

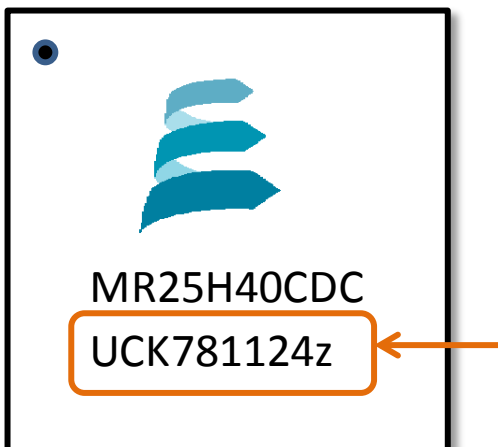
In the alternative format letter codes for wafer fabrication location and final test location will not be included in the trace code. The letter code for assembly location will be retained. *Wafer fabrication and test sites will always be traceable through the date code.*

This change applies to all products in all packages, effective December 30, 2011.

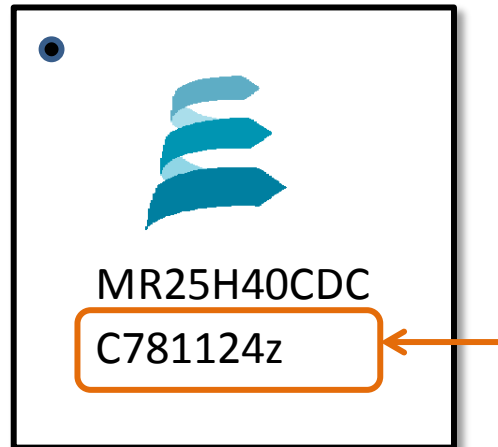
Material Differences

Example Package: Change applies to all products and packages

Current Trace Code



Alternative Trace Code



Current trace code format **FATWLYYWWz**

- F = Wafer FAB
- A = Assembly location
- T = Final Test Location
- WL = Wafer Lot Number
- YY = Year
- WW = Work Week
- z = Assembly lot split (may not be present)

Alternative trace code format **AWLYYWWz**

- A = Assembly location
- WL = Wafer Lot Number
- YY = Year
- WW = Work Week
- z = Assembly lot split (may not be present)

Products Affected

No.	1893	PCN Date	September 30, 2011	Effective Date	December 30, 2011
Title	Alternative Format for Trace Codes				

All products in all packages manufactured after December 30, 2011

Contact Information

Joe O'Hare, Director, Product Marketing
 Everspin Technologies
joe.ohare@everspin.com
 480-347-1111

Samples

Samples are not required.

Originator

<u>Date</u>	<u>Title</u>	<u>Name</u>
September 28, 2011	VP Marketing	Steffen Hellmold

Approval and Release

<u>Date</u>	<u>Title</u>	<u>Name</u>
September 30, 2011	VP Quality	Brad Engel